

CALIBRATION LABORATORIES

NVLAP LAB CODE 600214-0

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

<p><b>Additel Corporation</b> 2900 Saturn Street Brea, CA 92821 Eric Chavier Phone: 714-998-6899 Fax: 714-998-6999 E-mail: <a href="mailto:eric.chavier@additel.com">eric.chavier@additel.com</a> URL: <a href="http://additel.com">http://additel.com</a></p>	<p><b>Fields of Calibration</b> Electromagnetics Thermodynamics Time &amp; Frequency</p> <p>This laboratory is compliant to ANSI/NCSL Z540-1-1994; Part 1. (NVLAP Code: 20/A01)</p>
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**CALIBRATION AND MEASUREMENT CAPABILITY (CMC) <sup>Note 1,2</sup>**

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty <sup>Note 3,5</sup>	Remarks
<b>ELECTROMAGNETIC - DC/LOW FREQUENCY</b>			
<b>DC RESISTANCE AND CURRENT (20/E05)</b>			
DC Resistance – Generate, Fixed Instrument Based	1 Ω	103 μΩ	Fluke 5730A
	1.9 Ω	180 μΩ	
	10 Ω	250 μΩ	
	19 Ω	475 μΩ	
	100 Ω	1.0 mΩ	
	190 Ω	1.9 mΩ	
	1 kΩ	6.8 mΩ	
	1.9 kΩ	13 mΩ	
	10 kΩ	68 mΩ	
	19 kΩ	130 mΩ	
	100 kΩ	850 mΩ	
	190 kΩ	1.70 Ω	
	1 MΩ	13.3 Ω	
	1.9 MΩ	43.7 Ω	
	10 MΩ	420 Ω	
	19 MΩ	917 Ω	
DC Resistance – Generate, Fixed Resistors	100 MΩ	13.2 kΩ	Additel ADT280-PRS Reference Resistors with Additel ADT286 Ratio mode
	1 Ω	0.17 μΩ/Ω	
	25 Ω	0.24 μΩ/Ω	
	50 Ω	2.0 μΩ/Ω	



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Measured Parameter or Device Calibrated	Range	Expanded Uncertainty <sup>Note 3,5</sup>	Remarks
DC Resistance – Generate, Variable Instrument Based	100 Ω	0.24 μΩ/Ω	Fluke 7526A
	200 Ω	2.0 μΩ/Ω	
	400 Ω	2.0 μΩ/Ω	
	1 kΩ	0.28 μΩ/Ω	
	2 kΩ	2.0 μΩ/Ω	
	4 kΩ	2.0 μΩ/Ω	
	10 kΩ	0.33 μΩ/Ω	
DC Resistance - Measure	10 Ω, 400-Ω Range	12 mΩ	Agilent 3458A opt 2
	100 Ω, 400-Ω Range	12 mΩ	
	400 Ω, 400-Ω Range	10 mΩ	
	10 Ω, 4k Ω Range	230 mΩ	
	100 Ω, 4k Ω Range	230 mΩ	
DC Current - Generate	400 Ω, 4k Ω Range	231 mΩ	Fluke 5730A
	0 mA to 220 μA	40.46 μA/A + 6 nA	
	> 220 μA to 2.2 mA	45.20 μA/A + 7 nA	
	> 2.2 mA to 22 mA	45.20 μA/A + 40 nA	
	> 22 mA to 220 mA	44.16 μA/A + 0.7 μA	
DC Current – Measure	> 220 mA to 2.2 A	93.04 μA/A + 12 μA	Agilent 3458A opt 2
	0 to 100 μA	23.77 μA/A + 2.1 nA	
	> 100 μA to 1.0 mA	21.53 μA/A + 6 nA	
	> 1.0 mA to 10 mA	21.54 μA/A + 60 nA	
	> 10 mA to 100 mA	26.33 μA/A + 0.6 μA	
	> 100 mA to 1 A	86.75 μA/A + 12 μA	



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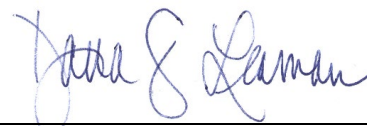
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CALIBRATION AND MEASUREMENT CAPABILITY (CMC) <sup>Note 1,2</sup>

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty <sup>Note 3,5</sup>	Remarks
<b>DC VOLTAGE (20/E06)</b>			
DC Voltage - Generate	0 mV to 220 mV >220 mV to 2.2 V >2.2 V to 11 V >11 V to 22 V >22V to 220 V >220 to 1100 V	9.19 $\mu\text{V/V} + 0.4 \mu\text{V}$ 5.25 $\mu\text{V/V} + 0.7 \mu\text{V}$ 3.47 $\mu\text{V/V} + 2.5 \mu\text{V}$ 3.47 $\mu\text{V/V} + 4 \mu\text{V}$ 4.92 $\mu\text{V/V} + 40 \mu\text{V}$ 6.38 $\mu\text{V/V} + 400 \mu\text{V}$	Fluke 5730A
DC Voltage - Measure	0 mV to 100 mV >100 mV to 1 V >1 V to 10 V >10 V to 100 V >100V to 1000 V	7.9 $\mu\text{V/V} + 0.4 \mu\text{V}$ 3.9 $\mu\text{V/V} + 0.4 \mu\text{V}$ 3.83 $\mu\text{V/V} + 0.6 \mu\text{V}$ 24.85 $\mu\text{V/V} + 40 \mu\text{V}$ 14.63 $\mu\text{V/V} + 110 \mu\text{V}$	Agilent 3458A opt 2
<b>TIME &amp; FREQUENCY</b>			
<b>FREQUENCY DISSEMINATION (20/F01)</b>			
Frequency - Generate	> 100 Hz to 50 kHz	1 $\mu\text{Hz/ Hz} + 2 \text{ nHz}$	Keysight 33512B
Frequency - Measure	> 100 Hz to 50 kHz	1 $\mu\text{Hz/ Hz} + 2 \text{ nHz}$	Keysight 53220A
<b>THERMODYNAMIC</b>			
<b>PRESSURE (20/T05)</b>			
Absolute Pressure Source - Pneumatic	5 kPa to 360 kPa  100 kPa to 7200 kPa 2 MPa to 72 MPa	0.0011 % + 0.64 Pa  0.0017 % + 6.58 Pa 0.0037% + 164 Pa	DHI PG7601 (10kPa)  DHI PG7601 (200kPa) DHI PG7202 (2MPa)
Gauge Pressure Source – Pneumatic <sup>Note 7</sup>	0 Pa to 750 Pa  750 Pa to 7500 Pa 5 kPa to 360 kPa 100 kPa to 7200 kPa 2 MPa to 72 MPa	0.095 Pa  0.085 Pa 0.0007 % + 0.53 Pa 0.002 % + 6.7 Pa 0.0037%+ 164 Pa	Fluke 7250LP  Fluke 7250LP DHI PG7601 (10kPa) DHI PG7601 (200kPa) DHI PG7202 (2MPa)
Gauge Pressure Source - Differential	-95 kPa to 10 kPa	0.003 % + 0.79 Pa	DHI PG7601 (10kPa)

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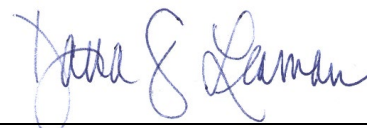
**NVLAP LAB CODE 600214-0**

**CALIBRATION AND MEASUREMENT CAPABILITY (CMC) <sup>Note 1,2</sup>**

Measured Parameter or Device Calibrated	Range	Expanded Uncertainty <sup>Note 3,5</sup>	Remarks
Gauge Pressure Source - Hydraulic	7 MPa to 275 MPa	0.0026% + 7.66 kPa	Minyu KY250
	7 MPa to 20 MPa	3.1 kPa	Fluke P3860-PS
	>20 MPa to 415 MPa	0.017%	Fluke P3860-PSI
<b>RESISTANCE THERMOMETRY (20/T07)</b>			
Drywell Calibrators	-40 °C to 0 °C	0.016 °C	Direct Comparison to SPRT
	>0 °C to 50 °C	0.011 °C	
	>50 °C to 155 °C	0.010 °C	
	>155 °C to 300 °C	0.019 °C	
	>300 °C to 450 °C	0.034 °C	
	>450 °C to 550 °C	0.053 °C	
	>550 °C to 660 °C	0.060 °C	
DryWell Calibrators	25 °C to 100 °C	0.40 °C	Direct Comparison to Reference grade Type S Thermocouple
	>100 °C to 300 °C	0.45 °C	
	>300 °C to 600 °C	0.50 °C	
	>600 °C to 900 °C	0.55 °C	
	>900 °C to 1210 °C	0.85 °C	
<b>TEMPERATURE INDICATORS (20/T08)</b>			
RTD Simulation - Measure	-180 °C to 0 °C	0.039 °C	Fluke 7526A PT385 (100 Ω) Measure Mode
	>0 °C to 800 °C	0.240 °C	
RTD Simulation - Generate	-180 °C to 800 °C	0.057 °C	
Thermocouple Simulation – Generate and Measure Type K	-200 °C to 0 °C	0.123 °C	Fluke 7526A Source and Measure
	> 0 °C to 660 °C	0.078 °C	
	> 660 °C to 1300 °C	0.100 °C	
Triple Point	0.01 °C	7.9 mK	Triple Point Water Cell with Accumac SPRT
<b>END</b>			

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Notes

**Note 1:** A Calibration and Measurement Capability (CMC) is a description of the best result of a calibration or measurement (result with the smallest uncertainty of measurement) that is available to the laboratory's customers under normal conditions, when performing more or less routine calibrations of nearly ideal measurement standards or instruments. The CMC is described in the laboratory's scope of accreditation by: the measurement parameter/device being calibrated, the measurement range, the uncertainty associated with that range (see note 3), and remarks on additional parameters, if applicable.

**Note 2:** Calibration and Measurement Capabilities are traceable to the national measurement standards of the U.S. or to the national measurement standards of other countries and are thus traceable to the internationally accepted representation of the appropriate SI (Système International) unit.

**Note 3:** The uncertainty associated with a measurement in a CMC is an expanded uncertainty with a level of confidence of approximately 95 %, typically using a coverage factor of  $k = 2$ . However, laboratories may report a coverage factor different than  $k = 2$  to achieve the 95 % level of confidence. Units for the measurand and its uncertainty are to match. Exceptions to this occur when marketplace practice employs mixed units, such as when the artifact to be measured is labeled in non-SI units and the uncertainty is given in SI units (Example: 5 lb weight with uncertainty given in mg).

**Note 3a:** The uncertainty of a specific calibration by the laboratory may be greater than the uncertainty in the CMC due to the condition and behavior of the customer's device and specific circumstances of the calibration. The uncertainties quoted do not include possible effects on the calibrated device of transportation, long term stability, or intended use.

**Note 3b:** As the CMC represents the best measurement results achievable under normal conditions, the accredited calibration laboratory shall not report smaller uncertainty of measurement than that given in a CMC for calibrations or measurements covered by that CMC.

**Note 3c:** As described in Note 1, CMCs cover calibrations and measurements that are available to the laboratory's customers under *normal conditions*. However, the laboratory may have the capability to offer special tests, employing special conditions, which yield calibration or measurement results with lower uncertainties. Such special tests are not covered by the CMCs and are outside the laboratory's scope of accreditation. In this case, NVLAP requirements for the labeling, on calibration reports, of results outside the laboratory's scope of accreditation apply. These requirements are set out in Annex A.5. of NIST Handbook 150, Procedures and General Requirements.

**Note 3d:** CMC expanded uncertainties include repeatability of best existing device (BED).

Note 4: Uncertainties associated with field service calibration may be greater as they incorporate on-site environmental contributions, transportation effects, or other factors that affect the measurements. (This note applies only if marked in the body of the scope.)

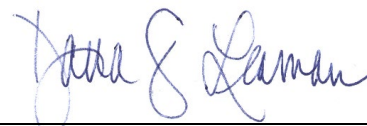
Note 5: Uncertainty values listed with percent (%) are percent of reading or generated value unless otherwise noted.

Note 6: NVLAP accreditation is the formal recognition of specific calibration capabilities. Neither NVLAP nor NIST guarantee the accuracy of individual calibrations made by accredited laboratories.

Note 7: Uncertainty applies to positive and negative pressures.

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